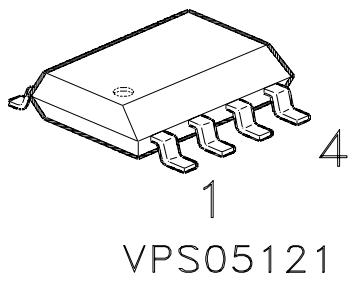
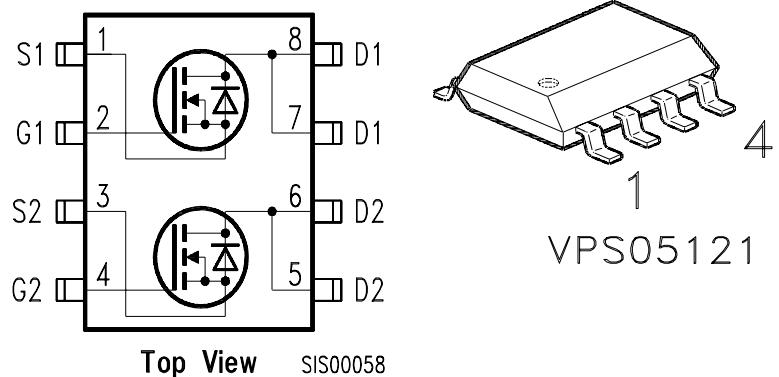


**SIPMOS® Small-Signal Transistor**

- Dual N-channel
- Enhancement mode
- Logic Level
- Avalanche rated
- $V_{GS(th)} = 1.2 \dots 2.0 \text{ V}$



Type	$V_{DS}$	$I_D$	$R_{DS(on)}$	Package	Marking	Ordering Code
BSO307N	30 V	4.2 A	0.075 $\Omega$	P-DSO-8		Q. .... - ....

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

**Maximum Ratings**

Parameter	Symbol	Values	Unit
Continuous drain current, <i>one channel active</i>	$I_D$	4.2	A
$T_A = 25^\circ\text{C}$			
Pulsed drain current, <i>one channel active</i>	$I_{Dpuls}$	16.8	
$T_A = 25^\circ\text{C}$			
Avalanche energy, single pulse	$E_{AS}$	-	mJ
$I_D = 4.2 \text{ A}$ , $V_{DD} = 25 \text{ V}$ , $R_{GS} = 25 \Omega$ $L = 6.23 \text{ mH}$ , $T_j = 25^\circ\text{C}$			
Avalanche current, repetitive, limited by $T_{j(max)}$	$I_{AR}$	4.2	A
Avalanche energy, periodic limited by $T_{j(max)}$	$E_{AR}$	-	mJ
Reverse diode dv/dt	dv/dt	-	KV/ $\mu\text{s}$
$I_S = 4.2 \text{ A}$ , $V_{DS} = 20 \text{ V}$ , $dI/dt = 200 \text{ A}/\mu\text{s}$ $T_{jmax} = 150^\circ\text{C}$			
Gate source voltage	$V_{GS}$	$\pm 14$	V
Power dissipation, <i>one channel active</i>	$P_{tot}$	2	W
$T_A = 25^\circ\text{C}$			
Chip or operating temperature	$T_j$	-55 ... + 150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 ... + 150	
IEC climatic category, DIN IEC 68-1		55 / 150 / 56	

**Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction-soldering point <sup>1)2)</sup>	$R_{thJS}$	-	30	-	K/W
Thermal resistance, chip to ambient <sup>1)2)</sup>	$R_{thJA}$	-	62.5	-	

1) Device on 50mm \* 50mm \*1.5mm epoxy PCB FR4 with 6 cm<sup>2</sup> copper area around the heat slug footprint(one layer, 70 µm copper).  
PCB is vertical without blown air.

2) one channel active

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

**Static Characteristics**

Drain- source breakdown voltage $V_{GS} = 0 \text{ V}$ , $I_D = 0.25 \text{ mA}$ , $T_j = 25^\circ\text{C}$	$V_{(BR)DSS}$	30	-	-	V
Gate threshold voltage $V_{GS}=V_{DS}$ , $I_D = 20 \mu\text{A}$	$V_{GS(\text{th})}$	1.2	1.6	2	
Zero gate voltage drain current $V_{DS} = 30 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_j = 25^\circ\text{C}$ $V_{DS} = 30 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_j = 125^\circ\text{C}$	$I_{DSS}$	-	0.1	1	$\mu\text{A}$
-	-	10	100		
Gate-source leakage current $V_{GS} = 20 \text{ V}$ , $V_{DS} = 0 \text{ V}$	$I_{GSS}$	-	10	100	nA
Drain-Source on-state resistance $V_{GS} = 4.5 \text{ V}$ , $I_D = 4.2 \text{ A}$	$R_{DS(\text{on})}$	-	0.055	0.075	$\Omega$

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Dynamic Characteristics</b>					
Transconductance $V_{DS} \geq 2 * I_D * R_{DS(on)max}$ , $I_D = 4.2 \text{ A}$	$g_{fs}$	3	6	-	S
Input capacitance $V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$	$C_{iss}$	-	400	500	pF
	$C_{oss}$	-	160	200	
Reverse transfer capacitance $V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$	$C_{rss}$	-	70	90	
	$t_{d(on)}$	-	22	33	
Turn-on delay time $V_{DD} = 15 \text{ V}$ , $V_{GS} = 4.5 \text{ V}$ , $I_D = 4.2 \text{ A}$ $R_G = 16 \Omega$	$t_r$	-	22	33	ns
	$t_{d(off)}$	-	22	33	
Fall time $V_{DD} = 15 \text{ V}$ , $V_{GS} = 4.5 \text{ V}$ , $I_D = 4.2 \text{ A}$ $R_G = 16 \Omega$	$t_f$	-	25	38	
	$Q_{g(th)}$	-	0.4	0.6	
Gate charge at threshold $V_{DD} = 15 \text{ V}$ , $I_D \geq 0.1 \text{ A}$ , $V_{GS}$ 0 to 1 V	$Q_{g(5)}$	-	8	12	nC
	$Q_{g(total)}$	-	13	20	
Gate plateau voltage $V_{DS} = 15 \text{ V}$ , $I_D = 4.2 \text{ A}$	$V_{(plateau)}$	-	3.2	-	V

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

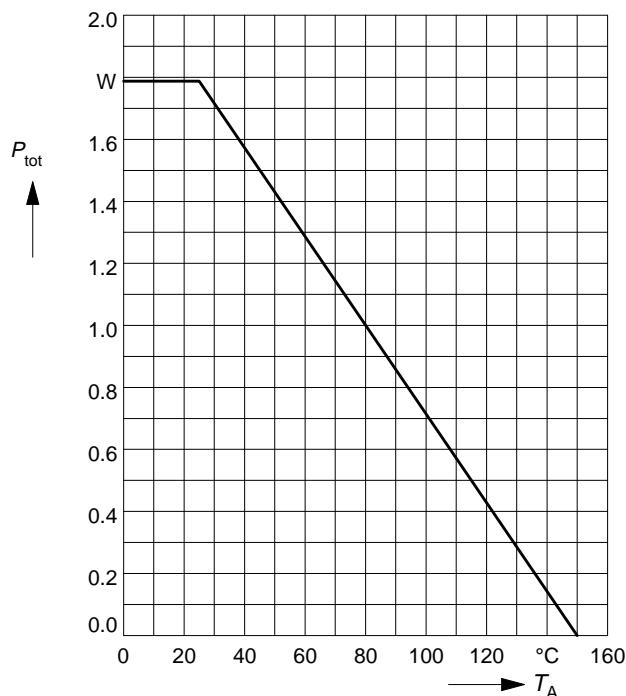
Parameter	Symbol	Values			Unit
		min.	typ.	max.	

### Reverse Diode

Inverse diode continuous forward current $T_A = 25^\circ\text{C}$	$I_S$	-	-	4.2	A
Inverse diode direct current,pulsed $T_A = 25^\circ\text{C}$	$I_{SM}$	-	-	16.8	
Inverse diode forward voltage $V_{GS} = 0 \text{ V}, I_F = 8.4 \text{ A}$	$V_{SD}$	-	0.85	1.1	V
Reverse recovery time $V_R = 15 \text{ V}, I_F=I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	$t_{rr}$	-	25	38	ns
Reverse recovery charge $V_R = 15 \text{ V}, I_F=I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	$Q_{rr}$	-	20	30	nC

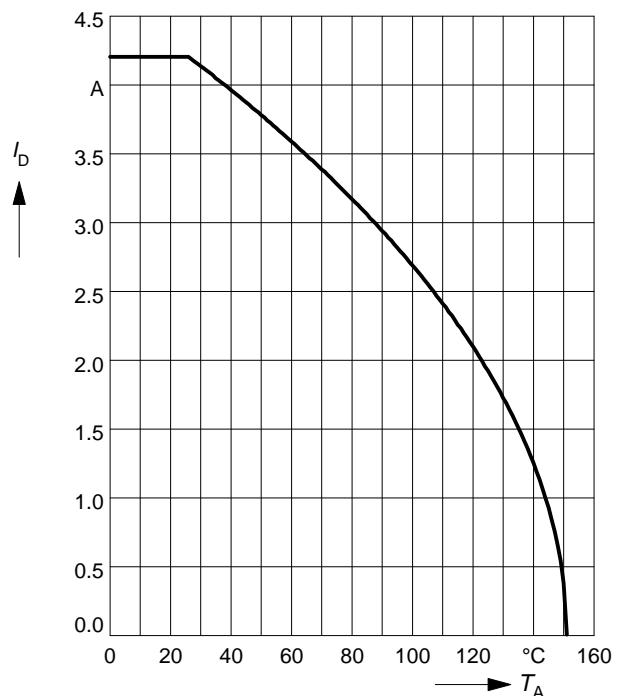
**Power dissipation**

$$P_{\text{tot}} = f(T_A)$$

**Drain current**

$$I_D = f(T_A)$$

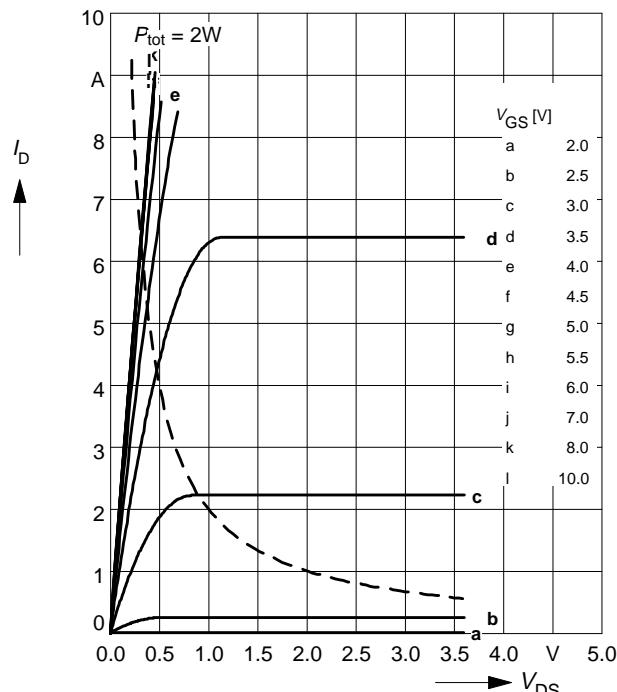
parameter:  $V_{GS} \geq 4$  V



### Typ. output characteristics

$$I_D = f(V_{DS})$$

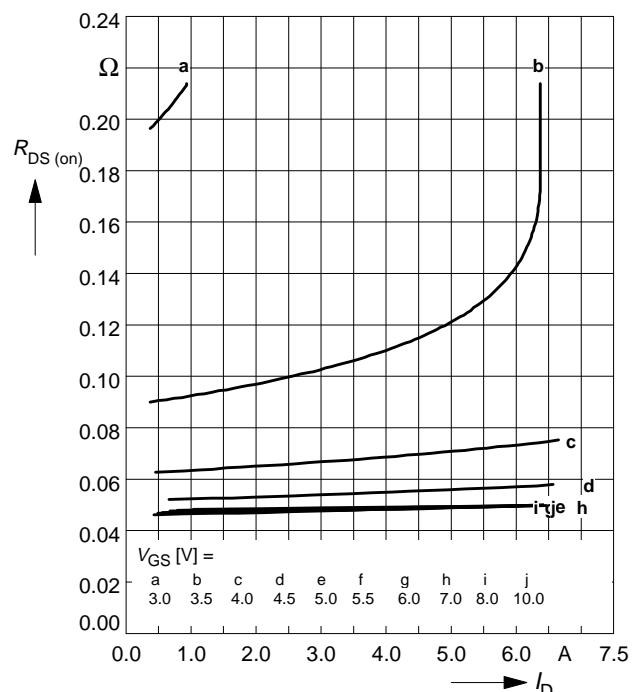
parameter:  $t_p = 80 \mu\text{s}$



### Typ. drain-source on-resistance

$$R_{DS(\text{on})} = f(I_D)$$

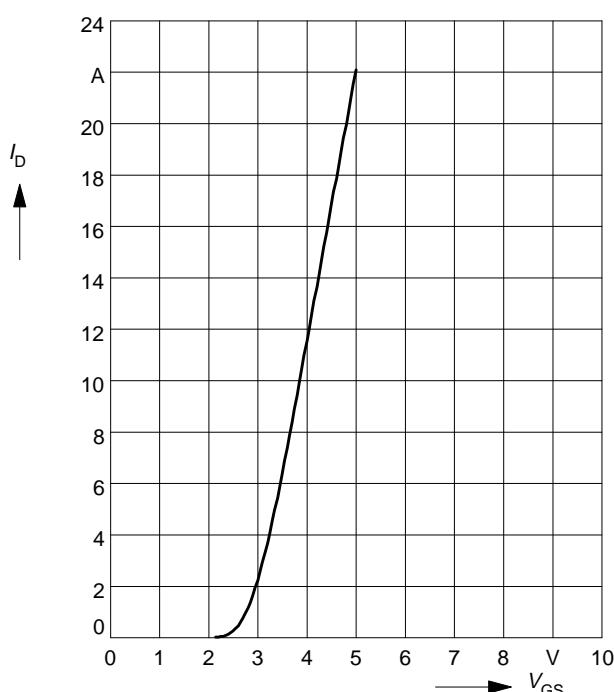
parameter:  $t_p = 80 \mu\text{s}, T_j = 25^\circ\text{C}$



### Typ. transfer characteristics $I_D = f(V_{GS})$

parameter:  $t_p = 80 \mu\text{s}$

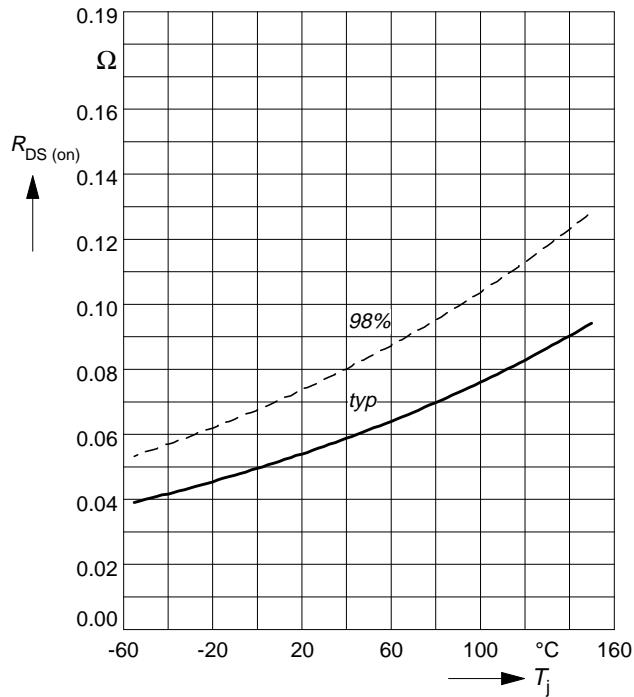
$$V_{DS} \geq 2 \times I_D \times R_{DS(\text{on})\text{max}}$$



### Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

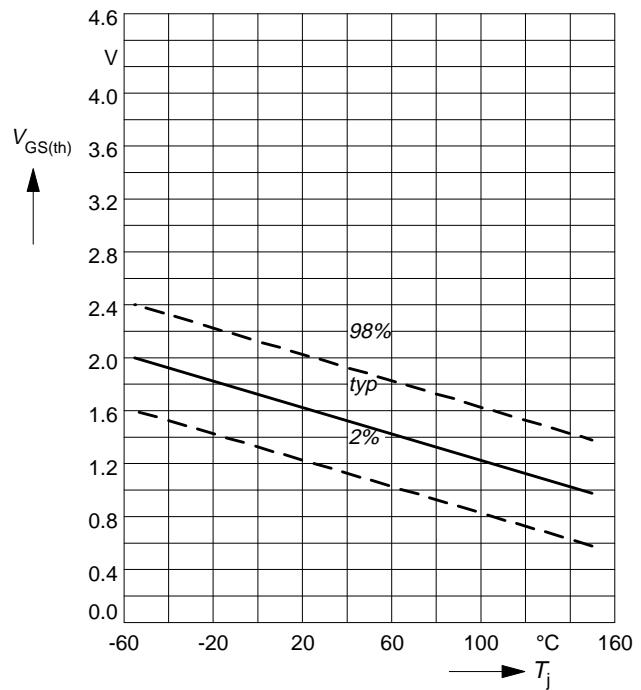
parameter:  $I_D = 4.2 \text{ A}$ ,  $V_{GS} = 4.5 \text{ V}$



### Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

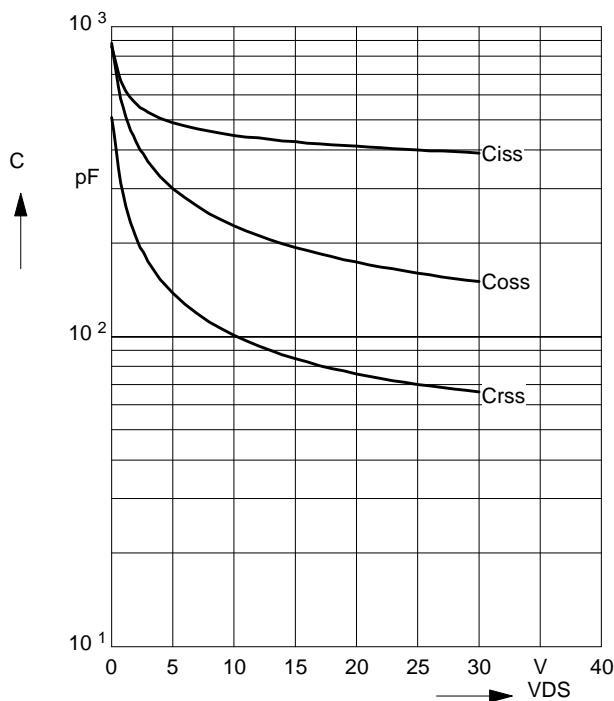
parameter:  $V_{GS} = V_{DS}$ ,  $I_D = 20 \mu\text{A}$



### Typ. capacitances

$$C = f(V_{DS})$$

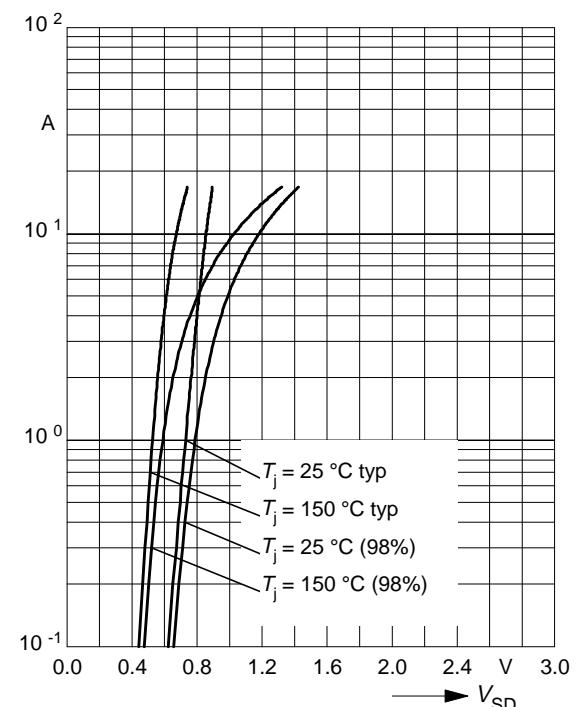
parameter:  $V_{GS}=0\text{V}$ ,  $f = 1 \text{ MHz}$



### Forward characteristics of reverse diode

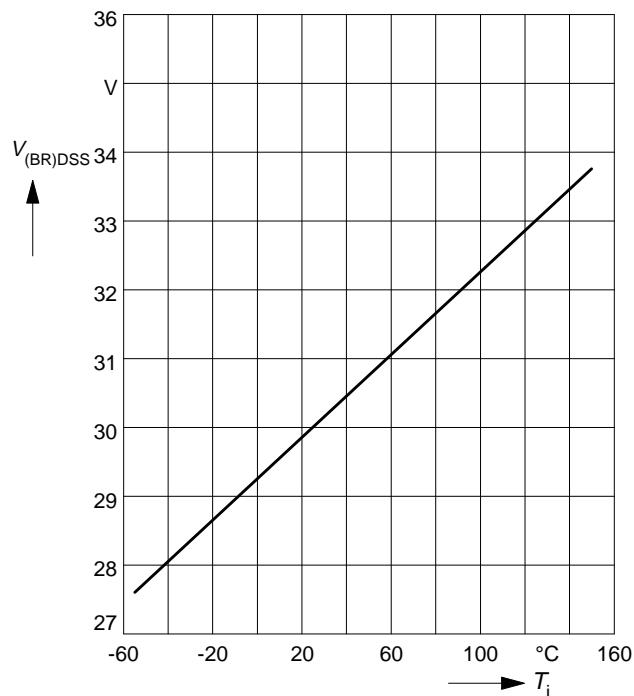
$$I_F = f(V_{SD})$$

parameter:  $T_j$ ,  $t_p = 80 \mu\text{s}$



**Drain-source breakdown voltage**

$$V_{(BR)DSS} = f(T_j)$$

**Typ. gate charge**

$$V_{GS} = f(Q_{Gate})$$

parameter:  $I_D$  puls = 4 A